

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	1	pattern adj inspect\$3 same reference adj pattern adj generator	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/16 14:02
L2	0	pattern adj inspect\$3 same reference adj pattern adj generator same(detect\$3 or determining)same pattern same designed adj data	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/16 14:04
L3	0	pattern adj inspect\$3 same reference adj pattern adj generator same(detect\$3 or determining)and pattern same designed adj data	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/16 14:04
L4	0	pattern adj inspect\$3 same reference adj pattern adj generator same(detect\$3 or determining)and pattern and designed adj data	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/16 14:04
L5	0	pattern adj inspect\$3 same reference adj pattern adj generator same designed adj data	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/16 14:05
L6	0	pattern adj inspect\$3 same reference adj pattern adj generator and designed adj data	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/16 14:05

L7	0	pattern adj inspect\$3 and reference adj pattern adj generator and designed adj data	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/16 14:05
L8	0	pattern adj inspect\$3 and reference adj pattern adj generator and designed adj data same detect\$3 adj pattern	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/16 14:06
L9	6	pattern adj inspect\$3 and reference adj pattern adj generator	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/16 14:07
L10	6	L9 and @ad<"20020821"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/16 14:08
L11	0	L10 and pattern adj inspect\$3 and reference adj pattern adj generator and designed adj data	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/16 14:10
L12	0	L10 and pattern adj inspect\$3 and reference adj pattern adj generator same detect\$3 adj pattern	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/16 14:12
L13	4	L10 and pattern adj inspect\$3 and reference adj pattern adj generator and detect\$3 adj pattern	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/16 14:12

L14	3	L13 and pattern adj inspect\$3 and reference adj pattern adj generator and detect\$3 adj pattern same (measurement or reference adj data or design or template or model)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/16 14:14
L15	0	L13 and pattern adj inspect\$3 and reference adj pattern adj generator and detect\$3 adj pattern same (defect\$3 or flaw or fault or reject\$3 or accept\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/16 14:16
L16	0	L13 and pattern adj inspect\$3 and reference adj pattern adj generator and detect\$3 adj pattern same (measurement or reference adj data or design or template or model)same(defect\$3 or flaw or fault or reject\$3 or accept\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/16 14:16
L17	3	L13 and pattern adj inspect\$3 and reference adj pattern adj generator and detect\$3 adj pattern same (measurement or reference adj data or design or template or model)and(defect\$3 or flaw or fault or reject\$3 or accept\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/16 14:17
L18	3	L17 and pattern adj inspect\$3 and(plurality or plural\$1) and(comparator or compar\$6)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/16 14:25
L19	3	L18 and pattern adj inspect\$3 and(plurality or plural\$1) and(comparator or compar\$6)same first and second	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/16 14:26
L20	3	L18 and pattern adj inspect\$3 and(plurality or plural\$1) and(comparator or compar\$6)same first same second	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/16 14:26

L21	1	L20 and(detect\$3 or determining)same(measurement or reference adj. data or design or template or model) same(defect\$3 or flaw or fault or reject\$3 or accept\$3)	US-PGPUB	OR	ON	2008/04/16 14:29
L22	1	L21 and @ad< "20020821"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/16 14:29
L23	0	L22 and (computer or memory or storage)and reads and stored and number and dimensional\$1 and pitch\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/16 14:31
L24	0	L22 and (computer or memory or storage)same reads same stored and number and dimensional\$1 and pitch \$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/16 14:32
L25	1	L22 and (computer or memory or storage)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/16 14:32
L26	0	L25 and reads same stored and number and dimensional\$1 and pitch\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/16 14:33
L27	0	L22 and (computer or memory or storage)and reads and stored and number and dimensional\$1 and pitch\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/16 14:33

L28	15890	(computer or memory or storage)and reads and stored and number and dimensional\$1 and pitch\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/16 14:33
L29	7	(computer or memory or storage)same reads same stored same number same dimensional\$1 same pitch\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/16 14:35
L30	6	L29 and @ad< "20020821"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/16 14:35
L31	0	L30 and(detect\$3 or determining)same(measurement or reference adj data or design or template or model) same(defect\$3 or flaw or fault or reject\$3 or accept\$3)	US-PGPUB	OR	ON	2008/04/16 14:36
L32	0	L30 and pattern adj inspect\$3 and reference adj pattern adj generator	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/16 14:39
L33	0	L30 and pattern adj inspect\$3 and reference same pattern adj generator	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/16 14:40
L34	0	L29 and pattern adj inspect\$3 and reference adj pattern adj generator	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/16 14:41

L35	0	L29 and pattern adj inspect\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/16 14:41
L36	0	L30 and pattern adj inspect\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/16 14:43
L37	0	L30 and pattern adj inspect\$3 and reference adj pattern adj generator and detect\$3 adj pattern same (measurement or reference adj data or design or template or model)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/16 14:45
L42	4	L13 and @ad<"20020821"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/16 14:49
L43	3	L42 and pattern adj inspect\$3 and reference adj pattern adj generator and detect\$3 adj pattern same (measurement or reference adj data or design or template or model)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/16 14:50
L44	0	L43 and (computer or memory or storage)and number and dimensional\$1 and pitch\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/16 14:51
L45	0	L43 and (computer or memory or storage)and number and dimension and pitch\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/16 14:52

L46	3	L43 and (computer or memory or storage)and(number or dimension or pitch\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/16 14:52
L48	3	L46 and @ad<"20020821"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/16 14:53
L49	0	L48 and(plurality or plural\$1)and repeated adj pattern and (measurement or reference adj data or design or template or model or reference adj pattern)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/04/16 15:01
S1	18	((HIDEO) near2 (TSUCHIYA)).INV.	US-PGPUB; USPAT	OR	ON	2006/12/20 09:57
S2	49	((KYOUJI) near2 (YAMASHITA)).INV.	US-PGPUB; USPAT	OR	ON	2006/12/20 09:57
S3	108	((TOSHIYUKI) near2 (WATANABE)).INV.	US-PGPUB; USPAT	OR	ON	2006/12/20 09:57
S4	8	((IKUNAO) near2 (ISOMURA)).INV.	US-PGPUB; USPAT	OR	ON	2007/07/26 16:53
S5	49	((TORU) near2 (TOJO)).INV.	US-PGPUB; USPAT	OR	ON	2006/12/20 09:58
S6	9	((YASUSHI) near2 (SANADA)).INV.	US-PGPUB; USPAT	OR	ON	2006/12/20 10:00
S7	4569	pattern adj inspect\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/20 10:00

S8	21	pattern adj inspect\$3 same(area or regions)same (measurement or reference adj data or design)same condition	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/20 10:02
S9	0	pattern adj inspect\$3 same(area or regions)same (measurement or reference adj data or design)same condition same(die adj die or die adj data adj base)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/09/11 13:17
S10	53	pattern adj inspect\$3 and(area or regions)and (measurement or reference adj data or design)and condition and(die adj die or die adj data adj base)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/09/11 12:14
S11	42	S10 and(@ad<"20020821" or @rlad<"20020821" or @prad<"20020821" or @ptad<"20020821")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/20 10:17
S12	19	S8 and(@ad<"20020821" or @rlad<"20020821" or @prad<"20020821" or @ptad<"20020821")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/20 10:54
S13	16	S8 and @ad<"20020821"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/20 10:11
S14	16	S12 and @ad<"20020821"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/20 10:06

S15	28	S11 and @ad<"20020821"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/09/11 13:11
S16	3	S1 and S8	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/20 10:13
S17	2	S16 and @ad<"20020821"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/20 10:13
S18	1	S1 and S10	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/20 10:12
S19	0	S18 and @ad<"20020821"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/20 10:14
S20	0	S2 and S8	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/20 10:14
S21	1	S2 and S10	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/20 10:13

S22	0	S21 and @ed<"20020821"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/20 10:14
S23	0	S3 and S8	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/20 10:14
S24	1	S3 and S'0	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/20 10:14
S25	0	S24 and @ed<"20020821"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/20 10:15
S26	0	S4 and S8	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/20 10:15
S27	2	S4 and S'0	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/20 10:14
S28	0	S27 and @ed<"20020821"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/20 10:15

S29	0	S5 and S8	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/20 10:15
S30	2	S5 and S10	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/20 10:15
S31	0	S30 and @ad<"20020821"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/20 15:27
S32	1	S6 and S8	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/20 10:15
S33	1	S6 and S10	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/20 10:15
S34	0	S32 and @ad<"20020821"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/20 10:16
S35	0	S33 and @ad<"20020821"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/20 10:16

S36	19	S8 and (@ad<"20020821" or @rlad<"20020821" or @prad<"20020821" or @ptad<"20020821")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/20 10:17
S37	16	S8 and @ad<"20020821"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/20 10:28
S38	100	((("5699447") or ("5982921") or ("6178257") or ("5900941") or ("6064484") or ("6072897") or ("4926489") or ("6091845") or ("6169603") or ("4603974") or ("5353116") or ("5576833") or ("5844809") or ("5978501") or ("4379259") or ("4520313") or ("4532650") or ("4778745") or ("4845558") or ("4860260") or ("5185812") or ("5355212") or ("5731982") or ("5917332") or ("5953579") or ("6040911") or ("6122397") or ("6272236") or ("6288780") or ("6356300") or ("6366690") or ("6396945") or ("6400839") or ("6477685") or ("6574524") or ("6603875") or ("6614520") or ("6628381") or ("6674889") or ("6803554") or ("6806456") or ("6828542") or ("6868175") or ("6884984") or ("6902855") or ("6969837") or ("6969864") or ("6973208") or ("6980686") or ("7032208") or (").pn.")).PN.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/09/11 14:07
S39	0	S38 and S8	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/20 10:28
S40	5	S38 and S10	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/20 10:28

S41	5	S40 and @ad<"20020821"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/20 10:34
S42	0	S41 and emitt\$3 adj light and electron adj beam	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/20 13:36
S43	0	S8 and emitt\$3 adj light and electron adj beam	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/20 11:11
S44	2	S10 and emitt\$3 adj light and electron adj beam	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/20 10:34
S45	1	S44 and @ad<"20020821"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/20 10:51
S47	4529	382/145,144,149,147,318,270,199,151.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/09/11 13:29
S48	4	S8 and S47	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/20 10:52

S49	3	S48 and @ad<"20020821"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/20 11:08
S50	5258	250/208.1,548,559.4.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/09/11 13:31
S51	27	S10 and S47	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/20 10:53
S52	15	S51 and @ad<"20020821"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/20 11:10
S53	3981	S47 and(@ad<"20020821" or @riad<"20020821" or @prad<"20020821" or @ptad<"20020821")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/20 10:56
S54	20	S51 and(@ad<"20020821" or @riad<"20020821" or @prad<"20020821" or @ptad<"20020821")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/09/11 13:16
S55	0	S50 and S10	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/20 10:58

S56	0	S50 and S8	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/20 10:57
S57	3913	356/394,390,237.4,237.1.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/09/11 13:30
S58	8	S57 and S10	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/20 10:59
S59	8	S58 and(@ad<"20020821" or @rtad<"20020821" or @prad<"20020821" or @ptad<"20020821")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/20 10:59
S60	5	S58 and @ad<"20020821"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/20 11:03
S61	1845	716/19,21.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/09/11 13:32
S62	0	S61 and S10	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/20 11:02

S63	420	348/126,130.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/20 11:04
S64	1	S63 and S10	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/20 11:02
S65	1	S64 and @ad<"20020821"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/20 13:24
S66	1096	348/126,130,61,125,129.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/09/11 13:32
S67	1	S66 and S10	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/20 11:05
S68	0	S49 and emitt\$3 adj light and electron adj beam	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/20 11:11
S69	1	S52 and emitt\$3 adj light and electron adj beam	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/20 11:13

S70	2	S54 and emitt\$3 adj light and electron adj beam	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/20 11:14
S71	0	S59 and emitt\$3 adj light and electron adj beam	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/20 11:14
S72	0	S60 and emitt\$3 adj light and electron adj beam	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/20 11:14
S73	0	S58 and emitt\$3 adj light and electron adj beam	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/20 11:15
S74	0	S65 and emitt\$3 adj light and electron adj beam	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/20 11:15
S75	2	"20040105578"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/20 13:24
S76	1	S75 and electron adj beam	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/20 13:35

S77	2201	inspect\$3 and electron adj beam and secondary adj electron	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/20 13:36
S78	26	S77 and stripe adj pattern	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/20 13:36
S79	3	S78 and emitt\$3 adj light and electron adj beam	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/20 13:37
S80	3	S78 and emitt\$3 adj light and electron adj beam	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/20 15:13
S81	6	((("6452677") or ("6204075") or ("5149976") or ("6087659).pn.")).PN.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/20 15:25
S82	11	((("3283898") or ("7113629") or ("6674890") or ("6614923") or ("6600491") or ("5727093).pn.")).PN.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/20 15:26
S83	9	S82 and @ad<"20020821"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/20 15:30

S84	0	S83 and vectors	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/12/20 15:30
S85	264	chawan-sheela\$.XA.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/26 16:53
S86	106	chawan-sheela\$.Xp.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/26 16:53
S87	13	S85 and pattern adj inspect\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/26 16:54
S88	4	S86 and pattern adj inspect\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/26 16:54
S89	5	S87 and (detect\$3 or determining)and reference adj image\$1 same defects	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/26 16:59
S90	2	S88 and (detect\$3 or determining)and reference adj image\$1 same defects	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/26 17:04

S91	5	S89 and @ad<"20020821"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/26 16:56
S92	1	S90 and @ad<"20020821"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/26 16:55
S93	10	S85 and (detect\$3 or determining)and reference adj image\$1 same defects	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/26 17:01
S94	4	S86 and (detect\$3 or determining)and reference adj image\$1 same defects	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/09/11 12:32
S95	4	S86 and (detect\$3 or determining)and reference adj image\$1 same defects	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/07/26 17:04
S96	64	pattern adj inspect\$3 and (area or regions)and (measurement or reference adj data or design)and condition and (die adj die or die adj data adj base)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/09/11 13:05
S98	9	S96 and optical adj imag\$3 and generat\$3 and detect \$3 adj pattern	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/09/11 12:20

S99	7	S96 and (reference adj image\$1 or template or model\$1) and pattern adj data and generat\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/09/11 12:35
S100	0	pattern adj inspect\$3 same (area or regions) same (detect \$3 or determining) same pattern adj data same (measurement or reference adj data or design or template or model) same condition same (die adj die or die adj data adj base)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/09/11 13:23
S101	14	pattern adj inspect\$3 same (area or regions) same (detect \$3 or determining) same pattern adj data same (measurement or reference adj data or design or template or model)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/09/11 13:08
S102	9	S101 same (detect \$3 or determining) same (measurement or reference adj data or design or template or model) same (defect \$3 or flaw or fault or reject \$3 or accept \$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/09/11 13:49
S103	6	S102 and @ad<"20020821"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/09/11 13:46
S104	8	S102 and (@ad<"20020821" or @rlad<"20020821" or @prad<"20020821" or @ptad<"20020821")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/09/11 13:28
S105	0	S103 and pattern adj inspect\$3 and (die adj die or die adj data adj base)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/09/11 13:19

S106	0	pattern adj inspect\$3 and(comparator or compar\$6) and pattern adj inspect\$3 and(die adj die or die adj data adj base)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/09/11 13:20
S107	86	pattern adj inspect\$3 and (plurality or plural\$1)and (comparator or compar\$6)and pattern adj inspect\$3 and (die adj die or die adj data adj base)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/09/11 13:39
S108	5	pattern adj inspect\$3 same(plurality or plural\$1)same (comparator or compar\$6)same pattern adj inspect\$3 same(die adj die or die adj data adj base)same pattern adj inspect\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/09/11 13:38
S109	1	pattern adj inspect\$3 same(plurality or plural\$1)same (comparator or compar\$6)same pattern adj inspect\$3 same(die adj die or die adj data adj base)same pattern adj inspect\$3 same(detected\$3 or determining)same (measurement or reference adj data or design or template or model)same(defect\$3 or flaw or fault or reject\$3 or accept\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/09/11 13:40
S111	0	S109 and(@ack-"20020821" or @rlack-"20020821" or @prad-"20020821" or @ptad-"20020821")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/09/11 14:16
S112	3204	382/145,144,149,147,318,270,199,151.ccls.	USPAT	OR	ON	2007/09/11 13:29
S113	1985	356/394,390,237.4,237.1.ccls.	USPAT	OR	ON	2007/09/11 13:30
S114	4209	250/208.1,548,559.4.ccls.	USPAT	OR	ON	2007/09/11 13:31
S115	1217	716/19,21.ccls.	USPAT	OR	ON	2007/09/11 13:32

S116	918	348/126,130,61,125,129.ccls.	USPAT	OR	ON	2007/09/11 13:32
S117	34	pattern adj inspect\$3 and (plurality or plural\$1)and (comparator or compar\$6)and pattern adj inspect\$3 and (die adj die or die adj data adj base)	USPAT	OR	ON	2007/09/11 13:33
S119	21	S112 and pattern adj inspect\$3 and (plurality or plural \$1)and (comparator or compar\$6)and pattern adj inspect\$3 and(die adj die or die adj data adj base)	USPAT	OR	ON	2007/09/11 13:34
S120	21	S119 and pattern adj inspect\$3 and(plurality or plural \$1)and(comparator or compar\$6)and pattern adj inspect \$3 and(die adj die or die adj data adj base)and pattern adj inspect\$3	USPAT	OR	ON	2007/09/11 13:36
S121	17	S120 and pattern adj inspect\$3 and(plurality or plural \$1)and(comparator or compar\$6)and pattern adj inspect \$3 and(die adj die or die adj data adj base)and pattern adj inspect\$3 and(detect\$3 or determining)and (measurement or reference adj data or design or template or model)and(defect\$3 or flaw or fault or reject\$3 or accept\$3)	USPAT	OR	ON	2007/09/11 13:38
S122	0	S112 same pattern adj inspect\$3 same(plurality or plural \$1)same(comparator or compar\$6)same pattern adj inspect\$3 same(die adj die or die adj data adj base) same pattern adj inspect\$3	USPAT	OR	ON	2007/09/11 13:38
S123	21	S112 and pattern adj inspect\$3 and(plurality or plural \$1)and (comparator or compar\$6)and pattern adj inspect\$3 and(die adj die or die adj data adj base)	USPAT	OR	ON	2007/09/11 13:39
S125	0	S123 and pattern adj inspect\$3 same(plurality or plural \$1)same(comparator or compar\$6)same pattern adj inspect\$3 same(die adj die or die adj data adj base) same pattern adj inspect\$3 same(detect\$3 or determining)same(measurement or reference adj data or design or template or model)same(defect\$3 or flaw or fault or reject\$3 or accept\$3)	USPAT	OR	ON	2007/09/11 13:41

S126	0	S113 and pattern adj inspect\$3 same(plurality or plural \$1) same(comparator or compar\$6) same pattern adj inspect\$3 same(die adj die or die adj data adj base) same pattern adj inspect\$3 same(detect\$3 or determining) same(measurement or reference adj data or design or template or model) same(defect\$3 or flaw or fault or reject\$3 or accept\$3)	USPAT	OR	ON	2007/09/11 14:10
S127	0	S114 and pattern adj inspect\$3 same(plurality or plural \$1) same(comparator or compar\$6) same pattern adj inspect\$3 same(die adj die or die adj data adj base) same pattern adj inspect\$3 same(detect\$3 or determining) same(measurement or reference adj data or design or template or model) same(defect\$3 or flaw or fault or reject\$3 or accept\$3)	USPAT	OR	ON	2007/09/11 13:42
S128	0	S115 and pattern adj inspect\$3 same(plurality or plural \$1) same(comparator or compar\$6) same pattern adj inspect\$3 same(die adj die or die adj data adj base) same pattern adj inspect\$3 same(detect\$3 or determining) same(measurement or reference adj data or design or template or model) same(defect\$3 or flaw or fault or reject\$3 or accept\$3)	USPAT	OR	ON	2007/09/11 13:42
S129	0	S116 and pattern adj inspect\$3 same(plurality or plural \$1) same(comparator or compar\$6) same pattern adj inspect\$3 same(die adj die or die adj data adj base) same pattern adj inspect\$3 same(detect\$3 or determining) same(measurement or reference adj data or design or template or model) same(defect\$3 or flaw or fault or reject\$3 or accept\$3)	USPAT	OR	ON	2007/09/11 13:43
S130	0	((pattern adj inspect\$3 same(plurality or plural\$1) same (comparator or compar\$6) same pattern adj inspect\$3 same(die adj die or die adj data adj base) same pattern adj inspect\$3 same(detect\$3 or determining) same (measurement or reference adj data or design or template or model) same(defect\$3 or flaw or fault or reject\$3 or accept\$3))). C.J.M.	US-PGPUB	OR	ON	2007/09/11 13:44

S131	2	((pattern adj inspect\$3 and(plurality or plural\$1)and (comparator or compar\$6)and pattern adj inspect\$3 and (die adj die or die adj data adj base)and pattern adj inspect\$3 and(detect\$3 or determining)and (measurement or reference adj data or design or template or model)and(defect\$3 or flaw or fault or reject\$3 or accept\$3))). C.L.M.	US-PGPUB	OR	ON	2007/09/11 13:45
S132	1	S131 and(@ad< "20020821" or @rlad< "20020821" or @prad< "20020821" or @ptad< "20020821")	US-PGPUB	OR	ON	2007/09/11 13:46
S133	1	S132 and @ad< "20020821"	US-PGPUB	OR	ON	2007/09/11 14:03
S134	0	S133 and(detect\$3 or determining)same(measurement or reference adj data or design or template or model) same(defect\$3 or flaw or fault or reject\$3 or accept\$3)	US-PGPUB	OR	ON	2007/09/11 13:49
S136	0	S133 and(detect\$3 or determining)same(measurement or reference adj data or design or template or model) same(defect\$3 or flaw or fault or reject\$3 or accept\$3)	US-PGPUB	OR	ON	2007/09/11 14:02
S139	0	S133 and(detect\$3 or determining)same(reference adj data or design or template)same(defect\$3 or flaw or fault or reject\$3 or accept\$3)	US-PGPUB	OR	ON	2007/09/11 14:03
S140	1	S131 and(detect\$3 or determining)same(reference adj data or design or template)same(defect\$3 or flaw or fault or reject\$3 or accept\$3)	US-PGPUB	OR	ON	2007/09/11 14:03
S141	0	S140 and @ad< "20020821"	US-PGPUB	OR	ON	2007/09/11 14:03

S142	100	((("5699447") or ("5982921") or ("6178257") or ("5900941") or ("6064484") or ("6072897") or ("4926489") or ("6091845") or ("6169603") or ("4603974") or ("5353116") or ("5576833") or ("5844809") or ("5978501") or ("4379259") or ("4520313") or ("4532650") or ("4778745") or ("4845558") or ("4860260") or ("5185812") or ("5355212") or ("5731982") or ("5917332") or ("5953579") or ("6040911") or ("6122397") or ("6272236") or ("6288780") or ("6356300") or ("6366690") or ("6396945") or ("6400839") or ("6477685") or ("6574524") or ("6603875") or ("6614520") or ("6628381") or ("6674889") or ("6803554") or ("6806456") or ("6828542") or ("6868175") or ("6884984") or ("6902855") or ("6969837") or ("6969864") or ("6973208") or ("6980686") or ("7032208") or ("").pn.")).PN.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/09/11 14:07
S144	0	S142 and pattern adj inspect\$3 same(plurality or plural \$1) same(comparator or compar\$6) same pattern adj inspect\$3 same(die adj die or die adj data adj base) same pattern adj inspect\$3 same(detect\$3 or determining) same(measurement or reference adj data or design or template or model) same(defect\$3 or flaw or fault or reject\$3 or accept\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/09/11 14:14
S145	2	"20040126003"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/09/11 14:15
S146	2	"7020321".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/09/11 14:15

S147	0	S145 and pattern adj inspect\$3 same(plurality or plural \$1) same(comparator or compar\$6) same pattern adj inspect\$3 same(die adj die or die adj data adj base) same pattern adj inspect\$3 same(detect\$3 or determining) same(measurement or reference adj data or design or template or model) same(defect\$3 or flaw or fault or reject\$3 or accept\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/09/11 14:14
S148	0	S146 and pattern adj inspect\$3 same(plurality or plural \$1) same(comparator or compar\$6) same pattern adj inspect\$3 same(die adj die or die adj data adj base) same pattern adj inspect\$3 same(detect\$3 or determining) same(measurement or reference adj data or design or template or model) same(defect\$3 or flaw or fault or reject\$3 or accept\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/09/11 14:14
S149	0	S145 and (@ad< "20020821" or @rlad< "20020821" or @prad< "20020821" or @ptad< "20020821")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/09/11 14:16
S150	0	S145 and @ad< "20020821"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/09/11 14:16

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